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<u>L6</u>	L3 and (scan\$ or label\$)
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<u>L4</u>	L3 and executable?
<u>L3</u>	L2 not l1
<u>L2</u>	(old adj1 (program? or file?)) and (new adj1 (program? or file?)) and difference?
<u>L1</u>	(difference near5 extract\$) near3 program?

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- 1** Identifying the semantic and textual differences between two versions of a program 100%



Susan Horwitz

ACM SIGPLAN Notices , Proceedings of the conference on Programming language design and implementation June 1990

Volume 25 Issue 6

Text-based file comparators (e.g., the Unix utility diff), are very general tools that can be applied to arbitrary files. However, using such tools to compare programs can be unsatisfactory because their only notion of change is based on program text rather than program behavior. This paper describes a technique for comparing two versions of a program, determining which program components r ...

- 2** Session 4 (full technical papers): evolution patterns and models: 100%



Evolution patterns of open-source software systems and communities

Kumiyo Nakakoji , Yasuhiro Yamamoto , Yoshiyuki Nishinaka , Kouichi Kishida , Yunwen Ye

Proceedings of the workshop on Principles of software evolution May 2002

Open-Source Software (OSS) development is regarded as a successful model of encouraging "natural product evolution". To understand how this "natural product evolution" happens, we have

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